

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/008,821	NA, WOON	
		Examiner	Art Unit	Page 1 of 1
		Paulos M. Natnael	2614	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,909,255 A	06-1999	Hatano, Takahisa	348/663
	B	US-6,738,097 B2	05-2004	Satoh, Yasunori	348/663
	C	US-5,091,783 A	02-1992	Miyaguchi, Hiroshi	348/24
	D	US-5,355,176 A	10-1994	Inagaki et al.	348/609
	E	US-4,641,180	02-1987	Richter, Hans-Peter	348/669
	F	US-5,029,001	07-1991	Tanaka et al.	348/447
	G	US-5,686,972	11-1997	Kim, Yeong-Taeg	348/663
	H	US-5,155,583 A	10-1992	Yoshimura et al.	348/665
	I	US-5,475,445 A	12-1995	Yamaguchi et al.	348/663
	J	US-5,134,467 A	07-1992	Kim, Kee H.	348/663
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.